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| Notice of References Cited | Application/Control No. 10/530,006 | Applicant(s)/Patent Under Reexamination KADONO ET AL. | |
| | Examiner Sara W. Crane | Art Unit 2811 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| * | A | US-6,532,164 | 03-2003 | Redon et al. | 365/97 |
| * | B | US-6,730,395 | 05-2004 | Covington, Mark William | 428/811.1 |
| * | C | US-6,987,302 | 01-2006 | Chen et al. | 257/368 |
| * | D | US-2004/0157449 | 08-2004 | Hidaka et al. | 438/689 |
| * | E | US-2002/0158342 | 10-2002 | Tuominen et al. | 257/784 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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